

<b>Notice of References Cited</b>	Application/Control No. 09/909,931		Applicant(s)/Patent Under Reexamination ABERG, ROBERT OLSON	
	Examiner Satish S. Rampuria		Art Unit 2191	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,371,851 A	12-1994	Pieper et al.	345/501
*	B	US-5,701,490 A	12-1997	Safonov, Vladimir Olegovich	717/143
*	C	US-5,966,532 A	10-1999	McDonald et al.	717/105
*	D	US-6,061,515 A	05-2000	Chang et al.	717/114
*	E	US-6,074,428 A	06-2000	Petler, Scott C.	716/2
*	F	US-6,138,270 A	10-2000	Hsu, Ray	717/125
*	G	US-6,173,208 B1	01-2001	Park et al.	700/83
*	H	US-6,185,728 B1	02-2001	Hejlsberg, Anders	717/109
*	I	US-6,269,474 B1	07-2001	Price, Thomas J.	717/104
*	J	US-2003/0120711 A1	06-2003	Katz, Alan A.	709/106
*	K	US-6,691,301 B2	02-2004	Bowen, Matt	717/114
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Pre-layout delay calculation specification for CMOS ASIC libraries, Edamatsu, H.; Homma, K.; Kakimoto, M.; Koike, Y.; Tabuchi, K., Feb 1998, Page(s): 241-248, IEEE
	V	An efficient computation of Euclidean distances using approximated look-up table, Chin-Chen Chang; Jer-Sheng Chou; Tung-Shou Chen, Volume: 10 Issue: 4 Jun 2000, Page(s): 594-599, IEEE
	W	Optimized look-up table for inter-mesurand compensation, Catunda, S.Y.C.; Naviner, J.-F.; Deep, G.S.; Freire, R.C.S., May 2001, Page(s): 128-132 vol.1, IEEE
	X	Table Look-Up MOSFET Modeling System Using a 2-D Device Simulator and Monotonic Piecewise Cubic Interpolation, Shima, T.; Tamada, H.; Ryo Luong; Mo Dang, Volume: 2 Issue: 2 April 1983, Page(s): 121- 126, IEEE

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.